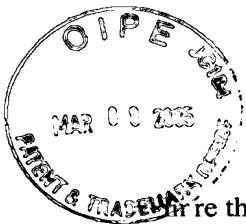


PATENT



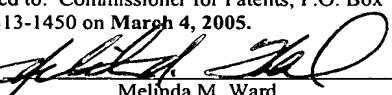
IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Re the application of:)
Gotkis et al.) Group Art Unit: 2855
Application No. 10/671,978) Examiner: DAVIS, O.
Filed: September 26, 2003) Atty. Docket No.: LAM2P438
For: METHOD AND APPARATUS FOR WAFER)
MECHANICAL STRESS MONITORING AND)
WAFER THERMAL STRESS MONITORING) Date: March 4, 2005

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450 on March 4, 2005.

Signed:


Melinda M. Ward

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449 may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§ 1.56 and 1.97. The Examiner is requested to consider these references and to acknowledge such consideration by initialing the attached PTO Form 1449 at the appropriate locations.

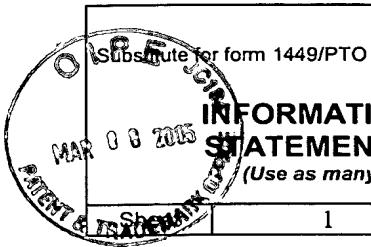
Applicants state that each item of information listed in the attached PTO Form 1449 was cited in a communication in a counterpart international application not more than three months prior to the filing of this statement.

Respectfully submitted,
MARTINE, PENILLA & GENCARELLA, LLP



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SEARCHED

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of

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Complete if Known	
Application Number	10/671,978
Filing Date	September 26, 2003
First Named Inventor	Gotkis
Art Unit	2855
Examiner Name	Davis
Attorney Docket Number	LAM2P438

U.S. Patent Documents

Examiner Initials	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
B	6,477,447		Nov. 5, 2002	Lin	
C	6,033,987		Mar 7, 2000	Tseng et al.	
A	5,196,353		Mar 23, 1993	Doan et al.	
D					
E					
F					
G					
H					

Foreign Patent Documents

Examiner Initial	Cite No. ¹	Foreign Patent Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ - Number ⁴ Kind Code ⁵ (if known)				
I	WO 03/002301		Jan 9, 2003	Gotkis et al.		<input type="checkbox"/>
J						<input type="checkbox"/>
K						<input type="checkbox"/>
L						<input type="checkbox"/>
M						<input type="checkbox"/>

Non Patent Literature Documents

Examiner Initial	Cite No.	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published
N		
O		
P		
Q		

Examiner Signature	Date Considered
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Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

¹Applicant's unique citation designation number (optional). ²See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³Enter Office that issued the document, by two-letter code (WIPO Standard ST.3). ⁴For Japanese patent documents, the indication of the year of the reign of Emperor must precede the serial number of the patent document. ⁵Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶Applicant is to place a check mark here if English language translation is attached.